

Search Notes

Application/Control No.

10/565,740

Examiner

Hien D. Vu

Applicant(s)/Patent under
Reexamination

NEUMETZLER, HEIKO

Art Unit

2833

SEARCHED

Class	Subclass	Date	Examiner
439	404	7/2/07	HV
↓	405		↓
	79		
	562		
↓	751		↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR